

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L6	182665	"438"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 16:19
L7	3	L6 and test\$3 and ((burn near in) or burnin or burn-in) and electromagnetic same wave	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 17:05
L8	5	L6 and test\$3 and ((burn near in) or burnin or burn-in) and test same (alternat\$3 near2 current)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 17:06
L9	8	L7 or L8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 17:05
L10	3	L9 and gate same oxide	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 16:37
L11	2	("5057441").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/03/22 16:29
L12	0	I11 and ((burn near in) or burnin or burn-in) and test same (alternat\$3 near2 current)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 16:30
L13	1	I11 and test same (alternat\$3 near2 current)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 16:30

EAST Search History

L14	1	I10 and electrode and (substrate or wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 16:36
L15	1	I10 and electrode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 16:36
L16	3	I10 and (substrate or wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 16:37
L17	3	(US-5548884-\$ or US-5798649-\$ or US-5648275-\$).did.	USPAT	OR	ON	2006/03/22 16:36
L18	3	I17 and (substrate or wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 16:37
L19	3	L18 and gate same oxide	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 16:57
L20	3	L19 and (metal or oxide or gate or electrode or (semiconductor near3 (apparatus or device)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 16:58
L21	5	L6 and test\$3 and ((burn near in) or burnin or burn-in) and test same ((alternat\$3 near2 current) or (electromagnetic same wave))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 17:07
L22	5	(US-5548884-\$ or US-5798649-\$ or US-6670201-\$ or US-5940680-\$ or US-5648275-\$).did.	USPAT	OR	ON	2006/03/22 17:07

EAST Search History

L23	5	L22 and test\$3 and ((alternat\$3 near2 current) or (electromagnetic same wave))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 17:11
L24	5	L22 and test\$3 and ((alternat\$3 same current) or (electromagnetic same wave)) and current	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 17:13
L25	2	L22 and test\$3 and ((alternat\$3 same current) or (electromagnetic same wave)) and current and ac and dc	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 17:13
S1	174897	"438"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/26 18:05
S2	261	S1 and wafer near2 (grind or grinding) and wafer same (mount or mounting or hold\$3) and (dicing or saw\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/26 18:07
S3	76	S2 and wire near2 bond\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/26 18:15
S5	174897	"438"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/29 09:52
S8	24737	438/106,108,110,111,112,113,114, 127,197,199,206,212,229,231,232, 234,262,299,301,305,306,455,458, 459,460,464,465,584,586,588,597, 598,599,612,618,622.cccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/29 10:11

EAST Search History

S11	174897	"438"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/29 22:35
S12	139	S11 and wire near2 bond\$3 and drop\$3 same (cure\$1 or curring or curing or dry\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/30 00:43
S16	4	(US-6419746-\$ or US-6372700-\$ or US-5707684-\$ or US-6503831-\$). did.	US-PGPUB; USPAT	OR	ON	2005/08/29 23:54
S37	25337	438/106,108,110,111,112,113,114, 127,197,199,206,212,229,231,232, 234,262,299,301,305,306,455,458, 459,460,464,465,584,586,588,597, 598,599,612,618,622.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/16 15:51
S45	177994	"438"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/17 16:36
S46	3	S45 and test\$3 and ((burn near in) or burnin or burn-in) and electromagnetic same wave	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/17 16:40
S47	49	test\$3 and ((burn near in) or burnin or burn-in) and electromagnetic same wave	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/17 16:39
S48	5	S45 and test\$3 and ((burn near in) or burnin or burn-in) and test same (alternat\$3 near2 current)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/17 16:41
S49	182665	"438"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 12:28

EAST Search History

S50	3	S49 and test\$3 and ((burn near in) or burnin or burn-in) and electromagnetic same wave	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 12:28
S51	5	S49 and test\$3 and ((burn near in) or burnin or burn-in) and test same (alternat\$3 near2 current)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 12:30
S52	8	S50 or S51	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 12:30
S53	3	S52 and gate same oxide	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 12:31